

About robustness of test patterns regarding multiple faults

Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan LATW 2012 : 13th IEEE Latin-American Test Workshop proceedings : April 10th-13th, 2012, Quito, Ecuador 2012 / p. 86-91 : ill <https://www.infona.pl/resource/bwmeta1.element.ieee-art-000006261243>

Diagnosis and correction of multiple design errors using critical path tracing and mutation analysis

Hantson, Hanno; Repinski, Urmaz; Raik, Jaan; Jenihhin, Maksim; Ubar, Raimund-Johannes LATW 2012 : 13th IEEE Latin-American Test Workshop proceedings : April 10th-13th, 2012, Quito, Ecuador 2012 / [6 p.] : ill <https://ieeexplore.ieee.org/document/6261234>

PSL assertion checkers synthesis with ASM based HLS tool ABELITE

Jenihhin, Maksim; Baranov, Samary; Raik, Jaan; Tihhomirov, Valentin LATW 2012 : 13th IEEE Latin-American Test Workshop proceedings : April 10th-13th, 2012, Quito, Ecuador 2012 / [6 p.] : ill <https://ieeexplore.ieee.org/document/6261251>